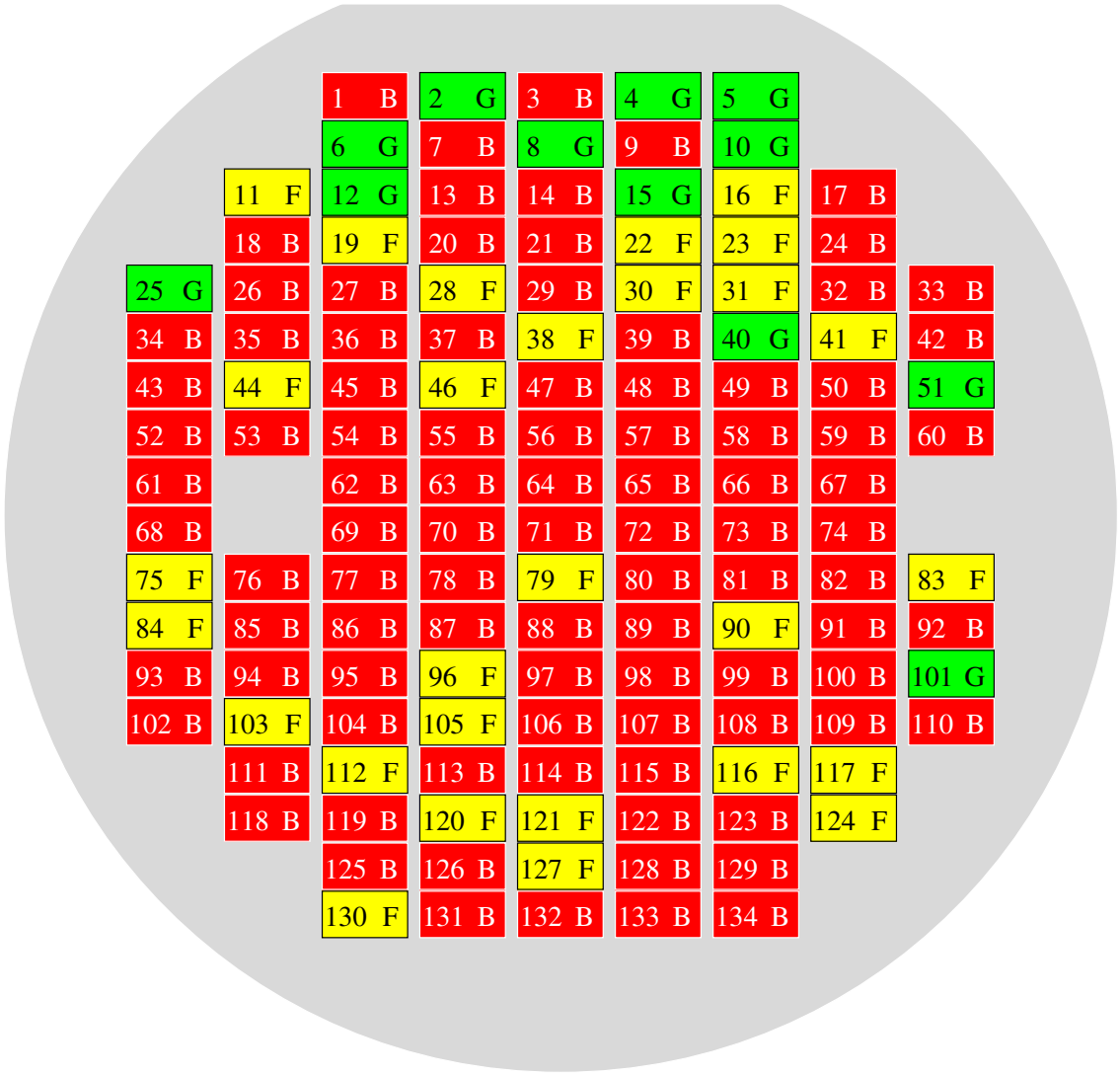
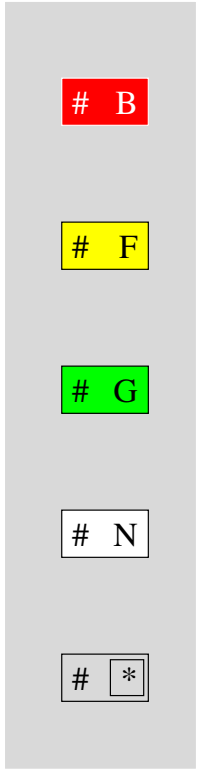
Die quality map for wafer 190 s/n: 21316-13-01

Date: 08/13/99





Bad die

Fair die

Good die

No info

Manually tagged